

RELIABILITY REPORT



RELIABILITY DATA
LT1112 / LT1114
8/21/2006

• OPERATING LIFE TEST

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS ⁽¹⁾ AT +125°C	NUMBER OF FAILURES ⁽²⁾
PLASTIC DIP	627	9422	9819	622.14	0
SOIC/SOT/MSOP	278 905	9736	0527	151.80 773.94	0 0

• HIGHLY ACCELERATED STRESS TEST AT +131°C/85%RH

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS ⁽⁴⁾ AT +85°C	NUMBER OF FAILURES
PLASTIC DIP	137 137	9410	9705	186.62 186.62	0 0

• PRESSURE COOKER TEST AT 15 PSIG, +121°C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS	NUMBER OF FAILURES
PLASTIC DIP	4,194	9245	0321	229.25	0
SOIC/SOT/MSOP	6,719 10,913	9248	0503	419.56 648.81	0 0

• TEMP CYCLE FROM -65°C to +150°C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
PLASTIC DIP	746	9245	0321	223.56	0
SOIC/SOT/MSOP	1,944 2,690	9248	0503	748.00 971.56	0 0

• THERMAL SHOCK FROM -65°C to +150°C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
PLASTIC DIP	204	9420	9545	118.19	0
SOIC/SOT/MSOP	1,284 1,488	9402	0402	343.17 461.36	0 0

(1) Assumes Activation Energy = 1.0 Electron Volts
(2) Failure Rate Equivalent to +55°C, 60% Confidence Level = 2.38 FITS
(3) Mean Time Between Failures in Years = 47,932
(4) Assumes 20X Acceleration from 85°C to +131°C
Note: 1 FIT = 1 Failure in One Billion Hours.